## STU7NF25



# N-channel 250 V, 0.29 Ω typ., 8 A STripFET™ II Power MOSFET in IPAK package

Datasheet - production data

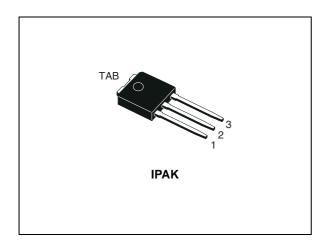
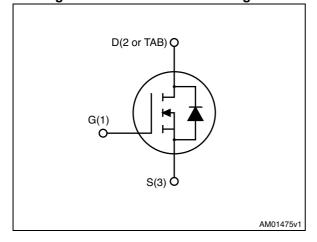


Figure 1. Internal schematic diagram



#### **Features**

Order code	V <sub>DSS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STU7NF25	250 V	0.42 Ω	8 A

- 100% avalanche tested
- 175 °C junction temperature

### **Applications**

Switching applications

#### **Description**

This Power MOSFET has been developed using STMicroelectronics' unique STripFET process, which is specifically designed to minimize input capacitance and gate charge. This renders the device suitable for use as primary switch in advanced high-efficiency isolated DC-DC converters for telecom and computer applications, and applications with low gate charge driving requirements.

**Table 1. Device summary** 

Order code	er code Marking Package		Packaging
STU7NF25	7NF25	IPAK	Tube

Contents STU7NF25

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STU7NF25 Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage	250	V
V <sub>GS</sub>	Gate-source voltage	±20	V
	Drain current (continuous) at T <sub>C</sub> = 25 °C	8	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> =100 °C	6	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	32	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	72	W
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 175	°C

<sup>1.</sup> Pulse width limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	2.08	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-amb max	100	C/VV

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I <sub>AV</sub>	Non-repetitive avalanche current	8	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting T <sub>J</sub> =25 °C, I <sub>D</sub> =I <sub>AV</sub> , V <sub>DD</sub> =50 V)	110	mJ

Electrical characteristics STU7NF25

## 2 Electrical characteristics

(T<sub>CASE</sub>=25 °C unless otherwise specified).

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	250	-		٧
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 250 V V <sub>DS</sub> = 250 V, T <sub>c</sub> =125 °C		-	1 50	μA μA
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ±20 V		-	±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	-	4	٧
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A		0.29	0.42	Ω

#### Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	500	-	pF
C <sub>oss</sub>	Output capacitance	V <sub>DS</sub> =25 V, f=1 MHz, V <sub>GS</sub> =0	-	90	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	, D3 - , , , d3 -	-	15	-	pF
Qg	Total gate charge	V <sub>DD</sub> = 200 V, I <sub>D</sub> = 8 A	-	16	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> =10 V	-	3.5	-	nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 14)	-	8	-	nC

#### Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD}$ =125 V, $I_{D}$ =4 A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ =10 V (see <i>Figure 13</i> and	-	13	-	ns
t <sub>r</sub>	Rise time		-	10	-	ns
t <sub>d(off)</sub>	Turn-off delay time		-	26	-	ns
t <sub>f</sub>	Fall time	Figure 18)	-	6	-	ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub>	Source-drain current Source-drain current (pulsed)		-		8 32	A A
V <sub>SD</sub>	Forward on voltage	I <sub>SD</sub> =8 A, V <sub>GS</sub> =0 V	-		1.5	٧
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 8 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s,}$	-	115		ns
Q <sub>rr</sub>	Reverse recovery charge	$V_{DD} = 50 \text{ V}$	-	470		nC
I <sub>RRM</sub>	Reverse recovery current	(see <i>Figure 15</i> )	-	8.5		Α
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 8 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s,}$	-	130		ns
Q <sub>rr</sub>	Reverse recovery charge	$V_{DD} = 50 \text{ V}, T_{J} = 150 \text{ °C}$	-	580		nC
I <sub>RRM</sub>	Reverse recovery current	(see <i>Figure 15</i> )	-	9.5		Α

Electrical characteristics STU7NF25

#### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

ting area Figure 3. Thermal impedance

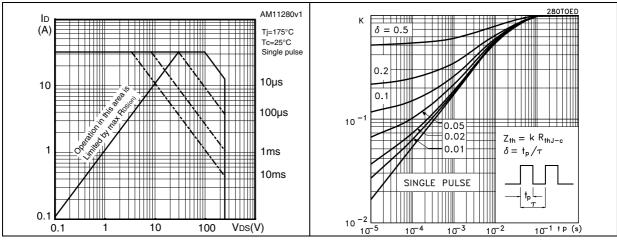


Figure 4. Output characteristics

Figure 5. Transfer characteristics

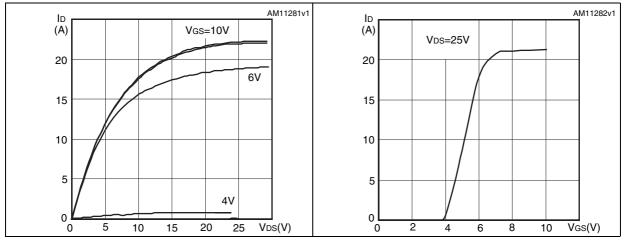
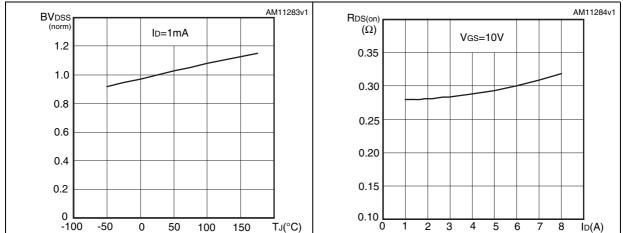


Figure 6. Normalized  $B_{VDSS}$  vs temperature

Figure 7. Static drain-source on-resistance



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Figure 8. Gate charge vs gate-source voltage

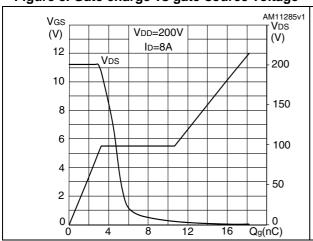


Figure 9. Capacitance variations

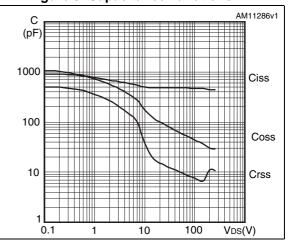
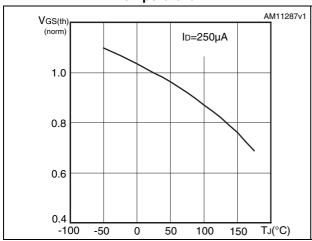


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on resistance vs temperature



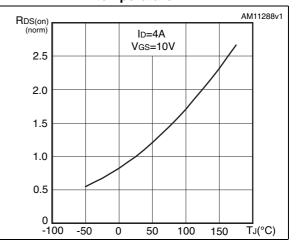
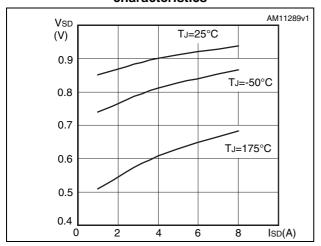


Figure 12. Source-drain diode forward characteristics



Test circuits STU7NF25

## 3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

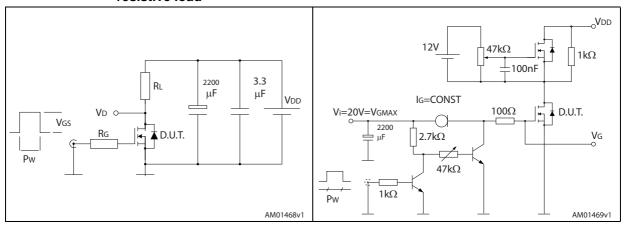


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

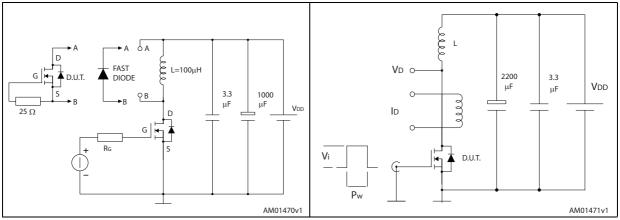
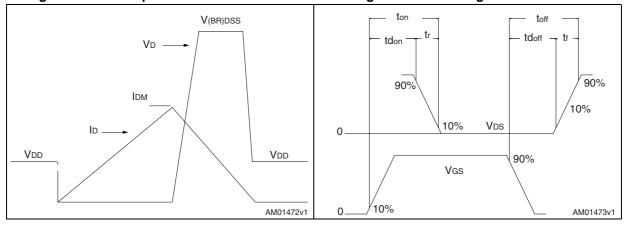


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform



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## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 9. IPAK (TO-251) mechanical data

DIM	,	mm.	
DIM	min.	typ.	max.
Α	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
Е	6.40		6.60
е		2.28	
e1	4.40		4.60
Н		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	



Eb4-L2 D L1 *b2 (3x)* Н b (3x) V1 -*B5* -e1— 0068771\_K

Figure 19. IPAK (TO-251) drawing

STU7NF25 Revision history

# 5 Revision history

Table 10. Document revision history

Date	Revision	Changes
24-Jul-2013	1	First release.

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